

Description

BACKGROUND OF THE INVENTION

This invention relates generally to a semiconductor integrated circuit device, and more particularly to technique which is effective when applied to a semiconductor integrated circuit device having a microcomputer function, for example.

In a 1-chip microcomputer, for instance, predetermined data processing is made in accordance with a program written into its built-in read-only memory (ROM). If a circuit arrangement is made in such a manner as to output the programmed data of this built-in ROM to an external terminal, there occurs the possibility that the content of the program will be known to a third party, and this is undesirable from the aspect of protection of software. However, the program content must be read out to the external terminal in order to test the memory.

As one prior art reference relating to the 1-chip microcomputer, mention can be made of "HITACHI MICROCOMPUTER DATA BOOK, 8-BIT SINGLE CHIP" published by Hitachi, Ltd., September, 1983.

GB-A-2 092 338 describes a memory in chip form in which external access to a program stored therein is physically disconnectable within the chip by a signal generated subsequent to the entry and checking of the program.

SUMMARY OF THE INVENTION

It is a primary object of the present invention to provide a semiconductor integrated circuit device which satisfies both the functions of the security of the programmed data of its built-in memory and the test of the memory.

The invention is defined by claim 1.

The objects and features of the present invention will become more apparent from the following description when taken in conjunction with the accompanying drawings.

BRIEF DESCRIPTION OF THE DRAWINGS

Fig. 1 is a block diagram of a 1-chip microcomputer to which the present invention is applied;
Fig. 2 is a circuit diagram of a comparison circuit of the microcomputer shown in Fig. 1; and
Fig. 3 is a timing chart useful for explaining the test operation of the microcomputer shown in Fig. 1.

DESCRIPTION OF THE PREFERRED EMBODIMENTS

Fig. 1 is a block diagram of a 1-chip microcomputer in accordance with the present invention. In the drawing, the portion encompassed by dash lines is one LSI which constitutes as a whole a 1-chip microcomputer. It is formed on one semiconductor substrate such as a silicon substrate by known semiconductor integrated circuit production technique.

Symbol CPU represents a microprocessor, and its principal constituent block is shown in the drawing as a representative.

Symbol A represents an accumulator, X is an index register, CC is a condition code register, SP is a stack pointer, PCH and PCL are program counters, CPU-CONT is a CPU controller and ALU is an arithmetic logic unit.

The construction of the microprocessor CPU described above is well known in the art; hence, its detailed description will be omitted.

Symbol I/O represents an input/output port, which includes therein a data transfer bidirectional register. Symbol I represents an input-only port.

Symbol OSC represents an oscillator. Though not particularly limitative, the oscillator uses a quartz oscillator Xtal mounted to LSI and generates a high precision reference frequency signal. A clock pulse necessary in the microprocessor CPU is prepared from this reference frequency signal. The reference frequency signal is used as a reference time pulse for a timer, too. This timer consists of a counter COUNT, a prescaler PR and a controller CONT. These circuits OSC, PR, COUNT and COUNT consist of heretofore known circuits, respectively.

Symbol RAM represents a random access memory circuit or block which is used primarily as a memory circuit of temporary data. Though not particularly limitative, a known static random access memory is used as this random access memory.

Symbol ROM represents a read-only memory circuit or block, into which a program for various data processing is written. Though not particularly limitative, the read-only memory (ROM) of this embodiment consists of a mask ROM. This mask ROM comprises a plurality of word lines, a plurality of data lines crossing the word lines, respectively, and memory cells disposed at the points of intersection between the word lines and the data lines. The circuit block ROM further includes row and column address decoders for selecting the word lines and the data lines in accordance with row and column address signals supplied from the microprocessor CPU through the address bus, respectively. A precharge circuit and a sense amplifier

circuit are connected to the data lines. Namely, the mask ROM of this embodiment comprises a known circuit. The output of the sense amplifier circuit is used as the output of the read-only memory ROM, which consists of an 8-bit unit and is outputted to the data bus through an output circuit (not shown in Fig. 1).

Each of the circuit blocks described above is connected to each other by the buses BUS with the microprocessor being the center. The buses BUS includes the data bus, the address bus and the control bus.

In the microcomputer of this embodiment, the output of the programmed data of the read-only memory ROM to the external terminal or to the outside of LSI is inhibited for the security purpose. In other words, the microcomputer is not equipped with the operational function of delivering the content of the read-only memory ROM to the external terminal. The following comparison circuit CMP is disposed in order to easily test such a read-only memory ROM.

This comparison circuit CMP compares the content of the read-only memory ROM, which is read out onto the data bus, with an input signal supplied from the external terminal, judges coincidence and discordance between them and outputs the result of comparison to the external terminal TO. In this embodiment, the result of judgement to be delivered to the external terminal TO is produced once per a plurality of comparing operations in order to enhance the security. Incidentally, the comparison circuit CMP is operative in a test mode and judges the coincidence and discordance between the ROM content and the input signal (expected value) supplied from any of the input/output ports I/O or the input-only port I.

Fig. 2 is a circuit diagram of one example of the comparison circuit CMP.

In the test mode, the input-only port I becomes operative automatically, though this circuit arrangement is not particularly limitative, so that the input circuit DI transfers the signal supplied from the external terminal Din to the data bus in the bus BUS in synchronism with an inverted clock signal $\bar{\phi}$. Fig. 2 illustrates a typical example of one unit input circuit DI constituting the input-only port I. In the 8-bit single chip microcomputer, eight unit input circuits DI are disposed and 8-bit input signals are supplied to eight data buses, though this circuit arrangement is not particularly limitative.

The 8-bit input signal supplied to each data bus is held by a D-type flip-flop circuit F2, which receives the input signal, simultaneously with the inverted clock signal $\bar{\phi}$ (or in the low level period of the signal ϕ). This flip-flop circuit F2 consists of eight flip-flop circuits, too.

The programmed data of the read-only memory ROM are read out in synchronism with the non-inverted clock signal ϕ . In other words, the read signal of the read-only memory ROM is outputted to the data bus through the output circuit DO which is rendered operative by the clock signal ϕ . The output circuit DO consists of eight output circuits, too, and delivers the 8-bit read signal read out from the read-only memory ROM to the data bus.

The 8-bit read signal supplied to the data bus is held by a D type flip-flop circuit F1, which receives the input signal, in synchronism with the clock signal ϕ (in the high level period of the signal ϕ). This flip-flop circuit F1 consists of eight flip-flop circuits, too. Though not limitative in particular, the flip-flop circuits F1 and F2 may have a set terminal (or a preset terminal and a clear terminal). In such a case, a reset signal is supplied to the set terminal before the test mode, and the flip-flop circuits F1 and F2 can enter the set state, that is, the output can be set to the high level.

The signals received by the flip-flop circuits F1 and F2 are supplied to a digital comparator DC. The digital comparator DC consists of eight exclusive NOR circuits (coincidence/discordance circuits) and an eight input AND gate circuit that receives the outputs of the NOR circuits, respectively. The output of the flip-flop circuit F1 is supplied to one input terminal of each of the eight exclusive NOR circuits, and the output of the flip-flop circuit F2 is supplied to the other input terminal. The output of the AND gate circuit is used as the output of the digital comparator DC.

In order to further ensure the security, the output signal of the digital comparator DC is not as such delivered to the external terminal TO but is outputted through the next output control circuit in this embodiment, though this circuit arrangement is not particularly limitative. In other words, the output signal of the digital comparator is supplied to the input terminal D of the D type flip-flop circuit F3 through the AND gate G1. The output signal Q of this flip-flop circuit F3 is supplied to the input terminal D of the D type flip-flop circuit F4. The flip-flop circuit F3 receives its input signal by means of the non-inverted clock signal ϕ (in the high level period of the signal ϕ), while the flip-flop circuit F4 receives its input signal by means of the inverted clock signal $\bar{\phi}$ (in the low level period of the signal ϕ). These flip-flop circuits F3 and F4 are set by reset signals RES supplied to their set terminals S (or the preset terminal and the clear terminal) before the test mode. In other words, their outputs are at the high level.

The output signal of the flip-flop circuit F4 is supplied to the input terminal of the AND gate circuit G1 as its control signal on one hand, and is outputted to the external terminal TO as the result

of comparison through the AND gate G2, on the other. The output signal OC of the AND gate circuit G3, that receives the 4-bit address signals $a_0 - a_3$, is supplied to the other input of the AND gate circuit G2, though this is not particularly limitative. The lower 4 bits of the row or column address signal for the selection of the read-only memory ROM are used as the address signals $a_0 - a_3$. The row or column address signals are sequentially incremented or decremented in order to test the read-only memory ROM. Therefore, the lower 4 bits of the address signal that are incremented or decremented in the test rise to the high level once per 16 incrementation or decrementation. Accordingly, the output signal OC rises to the high level once per 16 accesses to the read-only memory ROM, and the test result is outputted to the external terminal TO at a rate of 1 to 16 test cycles.

The test result may be outputted at a rate of once per 2, 4, 8, 32, 64, ... accesses. This can be set by changing the bit number of the input to the gate circuit G3. The test result can be outputted at a rate of 1 to 16 accesses by inputting the output of each stage of a 4-stage ripple counter to the gate circuit G3. The ripple counter is counted up in synchronism with the clock signal ϕ or $\bar{\phi}$. Other counters can be likewise utilized. Thus, the test result can be output once per an arbitrary number of access times by changing the counter construction. In this case, random access can be made to the read-only memory in the test mode.

One example of the operation of the comparison circuit CMP will be described with reference to the timing chart shown in Fig. 3.

The flip-flop circuits F3 and F4 are set during the high level period of the reset signal RES before the test operation. In other words, their outputs are set to the high level. The AND gate circuit G1 is kept open.

Then, the test operation is started. Since the flip-flop circuit F3 operates in synchronism with the clock signal ϕ , the test operation is started from the clock signal $\bar{\phi}$ having the inverted phase.

The expected value EO corresponding to the programmed data of the read-only memory ROM to be read out is supplied to the data bus through the input-only port I in synchronism with the low level of the clock signal ϕ (the high level of the clock signal $\bar{\phi}$). This signal EO is held by the flip-flop circuit F2. Since the flip-flop circuit F3 is inoperative when the signal ϕ is at the low level, the output of the comparator DC is not taken thereinto. Therefore, the output of the flip-flop circuit F4 is kept at the high level.

Though not particularly limitative, the row and column address signals are supplied to the read-only memory ROM during the low level period of

the clock signal ϕ , and the 8-bit output signal of the read-only memory ROM is taken into by the output circuit DO.

Next, the programmed data RO of the read-only memory ROM are outputted from the output circuit DO to the data bus in synchronism with the high level of the clock signal ϕ . This read signal RO is received by the flip-flop circuit F1 in synchronism with the clock signal ϕ . The signal RO of the flip-flop circuit F1 and the expected value EO are compared with each other by the digital comparator DC. The output of this comparator DC is transmitted to the input terminal of the flip-flop circuit F3 through the AND gate circuit G1 and is received in synchronism with the high level of the clock signal ϕ .

If all the bits (8 bits) of the signal EO coincide with those of the signal RO, the output of the comparator DC is at the high level, so that the output signal of the flip-flop circuit F3 are kept at the high level as represented by solid line in Fig. 3. If any one of the bits of the signal EO is not in agreement with that of the signal RO, the comparator outputs the low level signal, so that the output signal of the flip-flop circuit F3 is inverted to the low level (logic "0") as represented by dotted line in the chart.

The output signal of the flip-flop circuit F3 is transmitted to the flip-flop circuit F4 in synchronism with the fall of the clock signal ϕ to the low level.

When the discordance signal (logic "0") is transmitted to the flip-flop circuit F4, the output of the flip-flop circuit F4 drops to the low level. As a result, the output of the AND gate circuit G1 is kept fixed at the low level. In other words, the AND gate circuit G1 is closed to inhibit the reception of the subsequent comparator outputs.

When the clock signal ϕ drops once again to the low level as described above, the input of the next expected value E1 is effected. Thereafter, the same operation is repeated, and the indirect read operation read-only memory ROM, that is, comparison with the expected value and output of judgement, makes it possible to test the memory.

In this embodiment, since only the comparison judgement output signal is delivered, decoding of the ROM content by the third party who does not know the ROM program content cannot be made.

The present invention provides the following effects.

- (1) The programmed data of ROM can be read out indirectly by supplying the expected value from the external terminal and outputting only the result of its comparison judgement. Accordingly, only those who know the content of ROM can test it.

(2) The expected value is supplied from the external terminal and is compared with the programmed content of the memory storing the security data, and only the result of comparison judgement is outputted. Therefore, the programmed content of the memory cannot be decoded substantially by those who do not know the content of the memory.

(3) Since the comparison judgement outputs of a plurality of times of comparison are outputted, it becomes unknown which expected value is wrong. Therefore, in order to decode the programmed content, the expected values consisting of an extremely large number of combinations must be generated, and decoding of the programmed content by the third party becomes substantially impossible. When one judgement result is outputted per 16 times of comparison operations for the 8-bit expected value as in the foregoing embodiment, the necessary number is as great as $2^{8 \times 16}$.

(4) In comparison with a circuit arrangement wherein the output function to the external terminal of ROM or the like is completely inhibited by fuse means or the like, the present invention makes it possible to test the content of the memory so long as one knows the expected value. Therefore, this is extremely convenient for defect analysis and maintenance on the market.

The built-in ROM may be various known programmable ROMs such as EPROM (erasable-programmable ROM), EEPROM (electrically erasable-programmable PROM) to which data are written electrically.

It is also possible to employ the arrangement wherein the sequence for establishing the test mode is not laid open or a keyword is required for establishing the test mode. Such an arrangement can further enhance the security of the programmed content.

Various forms may be used for the system configuration of the 1-chip microcomputer. For example, a switch which is turned ON only in the test mode may be disposed between each data bus and each of the flip-flop circuits F1 and F2. Signals other than the signal ϕ may be supplied to the circuit DI and DO at times other than the test mode. Additional circuits such as A/D converters and the like may be further incorporated in order to expand the functions of the microcomputer. The built-in ROM may be of such a type into which data are written.

The present invention can be widely applied to semiconductor integrated circuits having the microcomputer function such as the 1-chip microcomputer or IC cards, or to semiconductor integrated circuit devices which are equipped with a built-in

ROM and which process signals in accordance with the content of ROM, or semiconductor memory device.

5 Claims

1. A semiconductor integrated circuit device comprising
a memory circuit (ROM) the output of programmed data of which is adapted to be inhibited to an external terminal (TO),
characterised by a comparing circuit (CMP) for comparing the programmed data read out from said memory circuit (ROM) with an input signal supplied from an external terminal (I, I/O), and out-putting the resulting coincidence or discordance signal to an external terminal (TO).
2. The device of claim 1, wherein said memory circuit comprises a read-only memory (ROM).
3. The device of claim 1 or 2, wherein the output of said coincidence or discordance signal is effected once after a plurality of said programmed data are compared with a plurality of said input signals corresponding to said programmed data.
4. The device of claim 3, wherein said programmed data is read out in a unit of a plurality of bits.
5. The device of claim 3 or 4, wherein the output of said coincidence or discordance signal is controlled by part of an address signal supplied to said memory circuit (ROM).
6. The device of claim 3 or 4, wherein the output of said coincidence or discordance signal is controlled by a counter circuit (COUNT) in synchronism with said comparison operation.
7. The device of any of claims 3 to 6, wherein said comparing circuit (CMP) includes holding means (F3, F4) for holding said coincidence or discordance signal, and inhibiting means (G1) for inhibiting the reception of subsequent results of comparison after one discordance signal is generated and held by said holding means (F3, F4).
8. The device of any of claims 1 to 7, which further comprises a microprocessor (CPU) which executes calculation on the basis of said programmed data of said memory circuit (ROM), and wherein said memory circuit

(2) The expected value is supplied from the external terminal and is compared with the programmed content of the memory storing the security data, and only the result of comparison judgement is outputted. Therefore, the programmed content of the memory cannot be decoded substantially by those who do not know the content of the memory.

(3) Since the comparison judgement outputs of a plurality of times of comparison are outputted, it becomes unknown which expected value is wrong. Therefore, in order to decode the programmed content, the expected values consisting of an extremely large number of combinations must be generated, and decoding of the programmed content by the third party becomes substantially impossible. When one judgement result is outputted per 16 times of comparison operations for the 8-bit expected value as in the foregoing embodiment, the necessary number is as great as $2^{8 \times 16}$.

(4) In comparison with a circuit arrangement wherein the output function to the external terminal of ROM or the like is completely inhibited by fuse means or the like, the present invention makes it possible to test the content of the memory so long as one knows the expected value. Therefore, this is extremely convenient for defect analysis and maintenance on the market.

The built-in ROM may be various known programmable ROMs such as EPROM (erasable-programmable ROM), EEPROM (electrically erasable-programmable PROM) to which data are written electrically.

It is also possible to employ the arrangement wherein the sequence for establishing the test mode is not laid open or a keyword is required for establishing the test mode. Such an arrangement can further enhance the security of the programmed content.

Various forms may be used for the system configuration of the 1-chip microcomputer. For example, a switch which is turned ON only in the test mode may be disposed between each data bus and each of the flip-flop circuits F1 and F2. Signals other than the signal ϕ may be supplied to the circuit DI and DO at times other than the test mode. Additional circuits such as A/D converters and the like may be further incorporated in order to expand the functions of the microcomputer. The built-in ROM may be of such a type into which data are written.

The present invention can be widely applied to semiconductor integrated circuits having the microcomputer function such as the 1-chip microcomputer or IC cards, or to semiconductor integrated circuit devices which are equipped with a built-in

ROM and which process signals in accordance with the content of ROM, or semiconductor memory device.

5 Claims

1. A semiconductor integrated circuit device comprising
a memory circuit (ROM) the output of programmed data of which is adapted to be inhibited to an external terminal (TO),
characterised by a comparing circuit (CMP) for comparing the programmed data read out from said memory circuit (ROM) with an input signal supplied from an external terminal (I, I/O), and out-putting the resulting coincidence or discordance signal to an external terminal (TO).
2. The device of claim 1, wherein said memory circuit comprises a read-only memory (ROM).
3. The device of claim 1 or 2, wherein the output of said coincidence or discordance signal is effected once after a plurality of said programmed data are compared with a plurality of said input signals corresponding to said programmed data.
4. The device of claim 3, wherein said programmed data is read out in a unit of a plurality of bits.
5. The device of claim 3 or 4, wherein the output of said coincidence or discordance signal is controlled by part of an address signal supplied to said memory circuit (ROM).
6. The device of claim 3 or 4, wherein the output of said coincidence or discordance signal is controlled by a counter circuit (COUNT) in synchronism with said comparison operation.
7. The device of any of claims 3 to 6, wherein said comparing circuit (CMP) includes holding means (F3, F4) for holding said coincidence or discordance signal, and inhibiting means (G1) for inhibiting the reception of subsequent results of comparison after one discordance signal is generated and held by said holding means (F3, F4).
8. The device of any of claims 1 to 7, which further comprises a microprocessor (CPU) which executes calculation on the basis of said programmed data of said memory circuit (ROM), and wherein said memory circuit



(ROM) consists of a read-only memory storing therein programs or data for said microprocessor (CPU).

9. The device of any of claims 1 to 8, including output means (G2) controlled by memory address signals (a0...a3) for passing said coincidence or discordance signal to said external terminal (TO).

10. The device of any of claims 1 to 9, and formed on an IC chip.

11. The device of any of claims 1 to 10, wherein said comparing circuit (CMP) includes
a digital comparator (DC),
a first gate circuit (G1) having a first input coupled to the output of said comparator (DC),
a first flip-flop (F3) coupled to the output of said first gate circuit (G1) and supplied with a first clock signal (ϕ), and

a second flip-flop (F4) coupled to an output of said first flip-flop (F3) and supplied with a second clock signal ($\bar{\phi}$) opposite in phase to said first clock signal (ϕ), the output of the second flip-flop (F4) being coupled to an output stage (G2),

wherein said first and second flip-flops (F3, F4) are respectively set to a first set of output levels when said comparator (DC) provides said coincidence signal, and to a second set of output levels when said comparator (DC) provides said discordance signal, and

wherein an output of said second flip-flop (F4) is coupled to a second input of said first gate circuit (G1) to fix said first gate circuit (G1) to a predetermined level inhibiting the passage of signals from said comparator (DC) to said first flip-flop (F3) when said first and second flip-flops (F3, F4) are at said second output levels.

12. The device of claim 11, wherein said output stage comprises a second gate circuit (G2) having its output connected to said external terminal (TO), a first input coupled to the output of said second flip-flop (F4) and a second input coupled to receive a control signal (OC) for controlling the timing of the application of said coincidence or discordance signal to said external terminal (TO).

13. The device of claim 12, comprising a third gate circuit (G3) having its output connected to the second input of said second gate circuit (G2) and its inputs coupled to receive address signals (a0...a3) designating a predetermined selection state of said memory circuit (ROM),

said third gate circuit (G3) generating said control signal (OC) when said address signals (a0...a3) indicate said predetermined selection state of said memory circuit (ROM).

Revendications

1. Dispositif à circuits intégrés à semi-conducteurs comprenant

un circuit de mémoire (ROM), dont la sortie des données programmées en direction d'un terminal extérieur (TO) est adaptée de manière à être inhibée,

caractérisé par un circuit comparateur (CMP) pour comparer les données programmées lues à partir dudit circuit de mémoire (ROM) à un signal d'entrée délivré par une borne extérieure (I, I/O), et envoyer le signal résultant de coïncidence ou de discordance audit terminal extérieur (TO).

2. Dispositif selon la revendication 1, dans lequel ledit circuit de mémoire comprend une mémoire morte (ROM).

3. Dispositif selon la revendication 1 ou 2, dans lequel la sortie dudit signal de coïncidence ou de discordance est effectuée après qu'une pluralité desdites données programmées ait été comparée avec une pluralité desdits signaux d'entrée correspondant auxdites données programmées.

4. Dispositif selon la revendication 3, dans lequel lesdites données programmées sont lues dans une unité formée d'une pluralité de bits.

5. Dispositif selon la revendication 3 ou 4, dans lequel la sortie dudit signal de coïncidence ou de discordance est commandée par une partie d'un signal d'adresse envoyé audit circuit de mémoire (ROM).

6. Dispositif selon la revendication 3 ou 4, dans lequel la sortie dudit signal de coïncidence ou de discordance est commandée par un circuit de comptage (COUNT) en synchronisme avec ladite opération de comparaison.

7. Dispositif selon l'une quelconque des revendications 3 à 6, dans lequel ledit circuit comparateur (CMP) comprend des moyens de maintien (F3, F4) servant à maintenir ledit signal de coïncidence ou de discordance, et des moyens d'inhibition (G1) pour inhiber la réception de résultats ultérieurs de comparaison une



fois qu'un signal de discordance a été produit et maintenu par lesdits moyens de maintien (F3,F4).

8. Dispositif selon l'une quelconque des revendications 1 à 7, qui comporte en outre un microprocesseur (CPU), qui exécute le calcul sur la base desdites données programmées dudit circuit de mémoire (ROM), et dans lequel ledit circuit de mémoire (ROM) est constitué d'une mémoire morte qui mémorise en elle des programmes ou des données pour ledit microprocesseur (CPU).

9. Dispositif selon l'une quelconque des revendications 1 à 8, comprenant des moyens de sortie (G2) commandés par des signaux d'adresses de mémoire (a0...a3) pour transmettre ledit signal de coïncidence ou de discordance audit terminal extérieur (TO).

10. Dispositif selon l'une quelconque des revendications 1 à 9, formé sur une microplaquette à circuits intégrés.

11. Dispositif selon l'une quelconque des revendications 1 à 10, dans lequel ledit circuit comparateur (CMP) comprend

un comparateur numérique (DC), un premier circuit de porte (G1) possédant une première entrée couplée à la sortie dudit comparateur (DC),

une première bascule bistable (F3) couplée à la sortie dudit premier circuit de porte (G1) et recevant un premier signal d'horloge (ϕ), et

une seconde bascule bistable (F4) couplée à une sortie de ladite première bascule bistable (F3) et alimentée par un second signal d'horloge ($\bar{\phi}$) possédant une phase opposée à celle dudit premier signal d'horloge (ϕ), la sortie de la seconde bascule bistable (F4) étant couplée à un étage de sortie (G2),

et dans lequel lesdites première et seconde bascules bistables (F3,F4) sont positionnées respectivement sur un premier ensemble de niveaux de sortie lorsque ledit comparateur (DC) délivre ledit signal de coïncidence, et sur un second ensemble de niveaux de sortie lorsque ledit comparateur (DC) délivre un signal de discordance, et

dans lequel une sortie de ladite seconde bascule bistable (F4) est couplée à une seconde entrée dudit premier circuit de porte (G1) pour fixer ledit premier circuit de porte (G1) à un niveau prédéterminé inhibant le passage de signaux dudit comparateur (DC) à ladite première bascule bistable (F3) lorsque lesdites

première et seconde bascules bistables (F3,F4) sont réglées sur lesdits seconds niveaux de sortie.

12. Dispositif selon la revendication 11, dans lequel ledit étage de sortie comprend un second circuit de porte (G2) dont la sortie est raccordée audit terminal extérieur (TO), et comportant une première entrée couplée à la sortie de ladite seconde bascule bistable (F4) et une seconde entrée couplée de manière à recevoir un signal de commande (OC) pour commander la cadence d'application dudit signal de coïncidence ou de discordance audit terminal extérieur (TO).

13. Dispositif selon la revendication 12, comprenant un troisième circuit de porte (G3), dont la sortie est raccordée à la seconde entrée dudit second circuit de porte (G2) et dont les entrées sont couplées de manière à recevoir des signaux d'adresses (a0...a3) désignant un état prédéterminé de sélection dudit circuit de mémoire (ROM), ledit troisième circuit de porte (G3) produisant ledit signal de commande (OC) lorsque lesdits signaux d'adresses (a0...a3) indiquent ledit état de sélection prédéterminé dudit circuit de mémoire (ROM).

30 Patentansprüche

1. Integrierte Halbleiterschaltung mit einem Speicherkreis (ROM), von dem die Ausgabe programmierter Daten an einen externen Anschluß (TO) inhibierbar ist,

gekennzeichnet durch einen Vergleichskreis (CMP) zum Vergleich der aus dem Speicherkreis (ROM) ausgelesenen programmierten Daten mit einem von einem externen Anschluß (I, I/O) zugeführten Eingangssignal und zur Ausgabe des sich ergebenden Koinzidenz- oder Diskordanzsignals an einen externen Anschluß (TO).

2. Schaltung nach Anspruch 1, wobei der Speicherkreis einen Festspeicher (ROM) umfaßt.

3. Schaltung nach Anspruch 1 oder 2, wobei die Ausgabe des Koinzidenz- oder Diskordanzsignals einmal erfolgt, nachdem mehrere der programmierten Daten mit mehreren ihnen entsprechenden Eingangssignalen verglichen worden sind.

4. Schaltung nach Anspruch 3, wobei die programmierten Daten als Einheit aus mehreren Bits ausgelesen werden.



5. Schaltung nach Anspruch 3 oder 4, wobei die Ausgabe des Koinzidenz- oder Diskordanzsignals durch einen Teil eines dem Speicher-
kreis (ROM) zugeführten Adress-Signals ge-
steuert ist.

6. Schaltung nach Anspruch 3 oder 4, wobei die Ausgabe des Koinzidenz- oder Diskordanzsignals durch einen mit dem Vergleichsvorgang
synchronisierten Zählerkreis (COUNT) gesteuert ist.

7. Schaltung nach einem der Ansprüche 3 bis 6, wobei der Vergleichskreis (CMP) eine Halteeinrichtung (F3, F4) zum Halten des Koinzidenz- oder Diskordanzsignals aufweist, sowie eine Inhibiereinrichtung (G1), die den Empfang nachfolgender Vergleichsergebnisse verhindert, nachdem ein Diskordanzsignal erzeugt worden und in der Halteeinrichtung (F3, F4) gehalten ist.

Schaltung nach einem der Ansprüche 1 bis 7, ferner umfassend einen Mikroprozessor (CPU), der eine Berechnung aufgrund der programmierten Daten von dem Speicherkreis (ROM) durchführt, wobei der Speicherkreis (ROM) aus einem Festspeicher besteht, der Programme oder Daten für den Mikroprozessor (CPU) speichert.

9. Schaltung nach einem der Ansprüche 1 bis 8 mit einer durch Speicheradressensignale (a0...a3) gesteuerten Ausgangsstufe (G2) zur Weitergabe des Koinzidenz- oder Diskordanzsignals an den externen Anschluß (TO).

10. Schaltung nach einem der Ansprüche 1 bis 9, die auf einem integrierten Halbleiterchip ausgebildet ist.

11. Schaltung nach einem der Ansprüche 1 bis 10, wobei der Vergleichskreis (CMP) umfaßt:

einen Digitalkomparator (DC),

eine erste Gatterstufe (G1) mit einem mit dem Ausgang des Komparators (DC) gekoppelten ersten Eingang,

ein mit dem Ausgang der ersten Gatterstufe (G1) gekoppeltes und mit einem ersten Taktsignal (ϕ) gespeistes erstes Flipflop (F3), und

ein mit dem Ausgang des ersten Flipflops (F3) gekoppeltes und mit einem zu dem ersten Taktsignal (ϕ) gegenphasigen zweiten Taktsignal ($\bar{\phi}$) gespeistes zweites Flipflop (F4), dessen Ausgang mit einer Ausgangsstufe (G2) gekoppelt ist,

wobei das erste und das zweite Flipflop

(F3, F4) auf einen ersten Satz von Ausgangspegeln gelegt sind, wenn der Komparator (DC) das Koinzidenzsignal erzeugt, bzw. auf einen zweiten Satz von Ausgangspegeln, wenn der Komparator (DC) das Diskordanzsignal erzeugt, und

wobei ein Ausgang des zweiten Flipflops (F4) mit einem zweiten Eingang der ersten Gatterstufe (G1) gekoppelt ist, um diese auf einem vorgegebenen Pegel zu fixieren, der die Weitergabe von Signalen von dem Komparator (DC) an das erste Flipflop (F3) inhibiert, wenn das erste und das zweite Flipflop (F3, F4) auf den zweiten Ausgangspegeln liegen.

12. Schaltung nach Anspruch 11, wobei die Ausgangsstufe eine zweite Gatterstufe (G2) umfaßt, die einen mit dem externen Anschluß (TO) verbundenen Ausgang, einen an den Ausgang des ersten Flipflops (F4) angeschlossenen ersten Eingang und einen zweiten Eingang zur Aufnahme eines Steuersignals (OC) zur Zeitsteuerung der Zuführung des Koinzidenz- oder Diskordanzsignals an den externen Anschluß (TO) aufweist.

13. Schaltung nach Anspruch 12, umfassend eine dritte Gatterstufe (G3), deren Ausgang an den zweiten Eingang der zweiten Gatterstufe (G2) angeschlossen ist und deren Eingänge Adressensignale (a0...a3) aufnehmen, die einen bestimmten Ansteuerzustand des Speicherkreises (ROM) angeben, wobei die dritte Gatterstufe (G3) das Steuersignal (OC) erzeugt, wenn die Adressensignale (a0...a3) den vorgegebenen Ansteuerzustand der Speicherschaltung (ROM) angeben.

